IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No	09/912,652
Filing Date	July 24, 2001
	Segal et al.
Assignee	Honeywell International Inc.
Examiner	H. Wilkins III
Attorney's Docket No	30-5004-DIV2
file: Methods for Controlling the Te	30-5004-DIV2 xture of Alloys Utilizing Equal Channel
Angular Extrusion	
000.	

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Mail Stop RCE

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

From: Jennifer J. Taylor, Ph.D. (Tel. 509-624-4276; Fax 509-838-3424)

Wells St. John P.S.

601 W. First Avenue, Suite 1300

Spokane, WA 99201-3828

Dear Sir:

The Examiner's attention is directed to the references which are listed on the attached Form PTO-1449 and copies of which are attached.

Citation of these references is respectfully requested.

Respectfully submitted,

ed: <u>Hugus</u> 10, 2009

By:

Jennifer J. Taylor,

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO. 30-5004(4015) DIV2

SERIAL NO. 09/912,652

LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)

APPLICANT Vladimir Segal et al. FILING DATE July 24, 2001

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	AG	, <u>, , , , , , , , , , , , , , , , , , </u>									
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449			U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE					SERIAL N 09/912,652				
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